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2785

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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JAN 24 2000

GROUP 2700

Applicant(s): H. SHISHIDO, et al  
Serial No.: 09/473,296  
Filed: December 28, 1999  
For: METHOD AND EQUIPMENT FOR DETECTING PATTERN  
DEFECT  
Group: 2785  
Examiner:

PRELIMINARY AMENDMENT

Commissioner for Patents  
Washington, D.C. 20231  
July 20, 2000

Sir:  
The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

IN THE SPECIFICATION:

Please replace the original specification with the attached Substitute Specification.

BEST AVAILABLE COPY

IN THE CLAIMS:

Please amend the claims as follows:

Claim 1, line 2, before "laser" (first occurrence) insert  
--a--; same line 2, delete "means";  
line 4, delete "means";  
line 14, delete "detecting an";  
line 15, delete "image of said sample".